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Supporting Information:

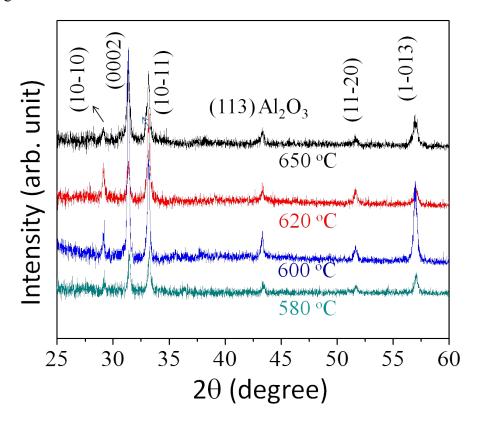


Figure S1. XRD pattern of InN samples grown at different temperatures.

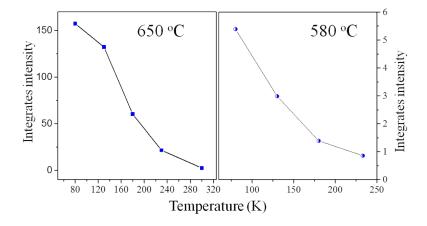


Figure S2. Temperature dependence of integrated PL intensity.